

**Search Notes**

Application/Control No.

10/069,516

Examiner

Jacob Meek

Applicant(s)/Patent under  
Reexamination

AIKAWA ET AL.

Art Unit

2637

**SEARCHED**

Class	Subclass	Date	Examiner
375	145,142 326,149 148,150 227	2/17/2006	JM
370	515,342	2/17/2006	JM
370	441,335	2/17/2006	JM
370	343	2/17/2006	JM
375	140	2/17/2006	JM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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